

#### A

# Design-of-Experiments (DOE) approach to FEM Uncertainty Analysis

for optimizing

## Magnetic Resonance Imaging RF Coil Design

COMSOL CONFERENCE 2014 BOSTON Jeffrey T. Fong, Ph.D., P.E.

Physicist and Project Manager

Applied & Computational Mathematics Division

National Institute of Standards & Technology

Gaithersburg, MD 20899-8910, U.S.A.

http://www.nist.gov/itl/math/Jeffrey-t-fong.cfm

(301) 975-8217 **fong@nist.gov** 



# Outline of Talk

(16 slides)

- (4) What is a "Design-of-Experiments" approach?
- (4) A Design Optimization Problem using FEM (via COMSOL-RF).
- (6) Solution before optimization.
- (1) Solution after optimization.
- (1) Future work.



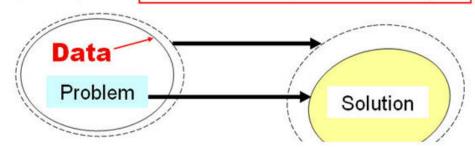


#### Metrological Approach - "Wiggle each FEM solution"

One "wiggles" an **FEM** solution by varying the input parameters and material property data in a *statistically* rigorous way, i.e., *design of experiments*, to calculate uncertainty within an affordable time frame and computing budget.

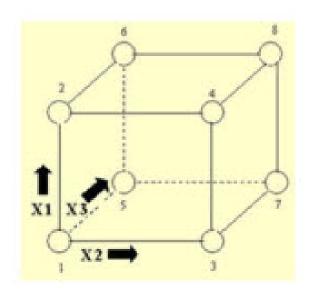
Such "wiggle" is the 3<sup>rd</sup> requirement of a "correct" problem:

Ref.: Garabedian, P. R., 1964, Partial Diff. Equations, page 109. Providence, RI: AMS Chelsea Publishing (1964). To be precise, we define a boundary or initial value problem for a partial differential equation, or for a system of partial differential equations, to be *correctly set in the sense of Hadamard* if and only if its solution exists, is unique, and depends continuously on the data assigned.





## Design of Experiments (Full vs. Fractional)



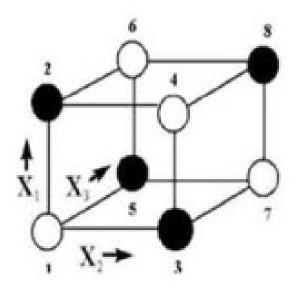
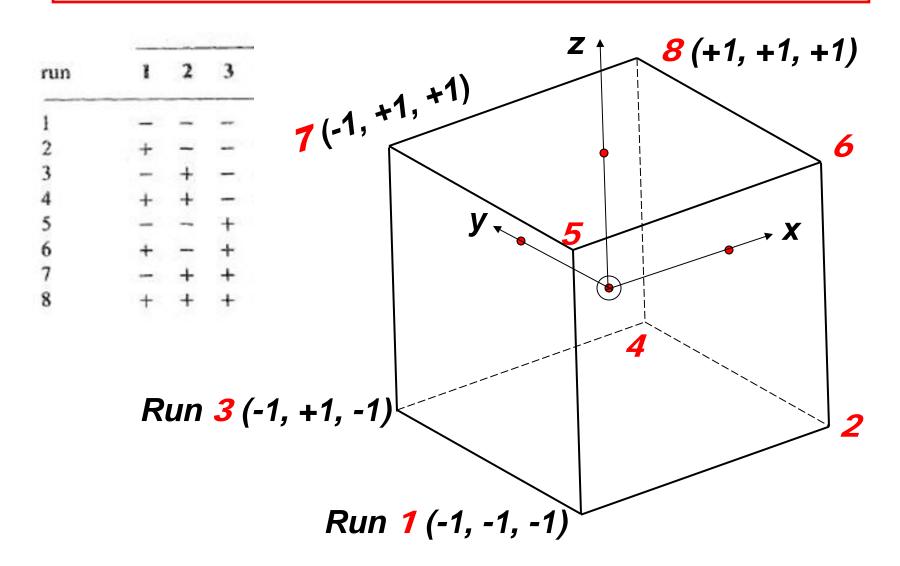


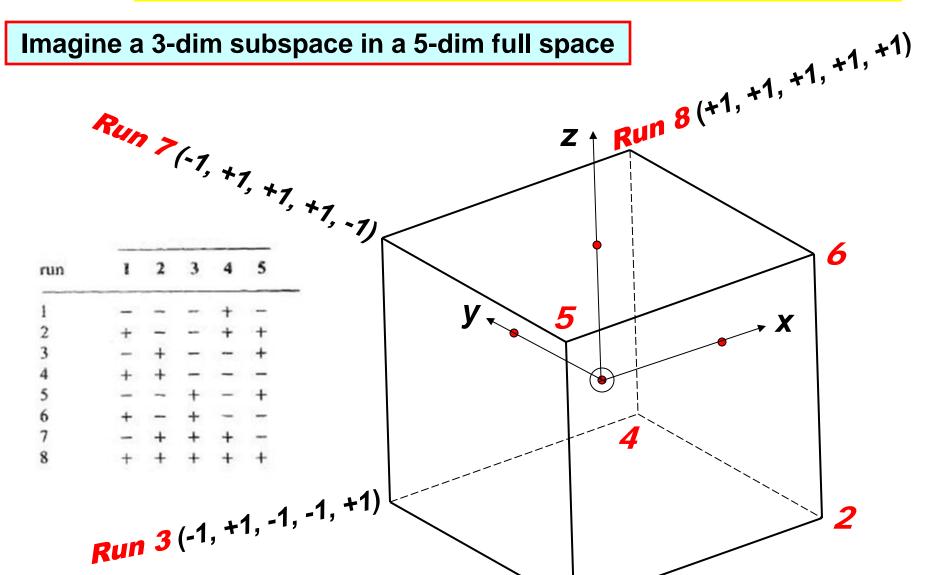
Figure 1. (left) A full-factorial 8-run orthogonal design for 3 factors. (right) A fractional factorial 4-run orthogonal design for 3 factors.



#### Metrological Approach - "Wiggle each FEM solution"

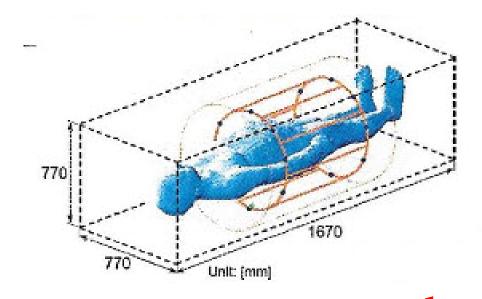




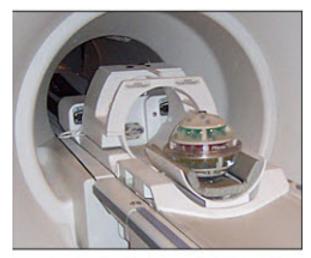


**Run 1** (-1, -1, -1, +1, -1)





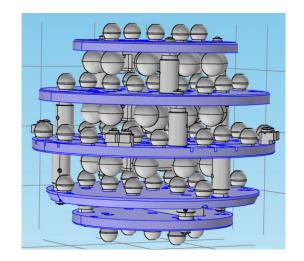






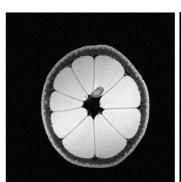
Jeffrey T. Fong, NIST, Gaithersburg, MD 20899 USA. Tel: 1-301-975-8217 Email: fong@nist.gov





## A Model Simplification Approach

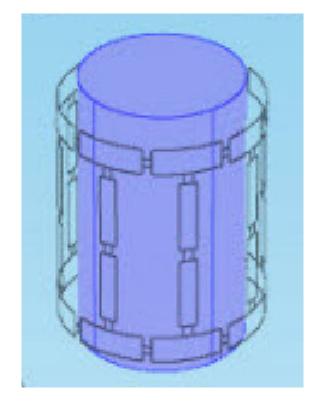




MRI image of a lemon (Courtesy of Dr. Steve Russek NIST, Boulder CO 80305)



MRI image of a banana (Courtesy of Dr. Steve Russek NIST, Boulder CO 80305)

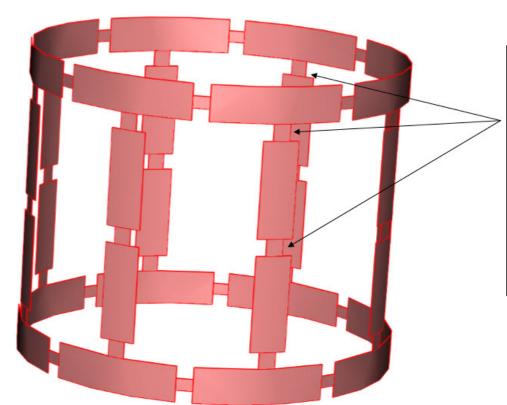






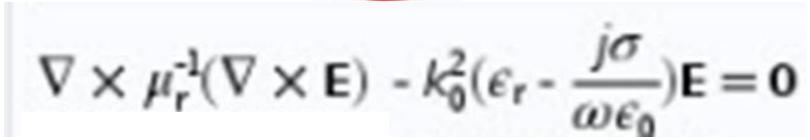


#### - MRI

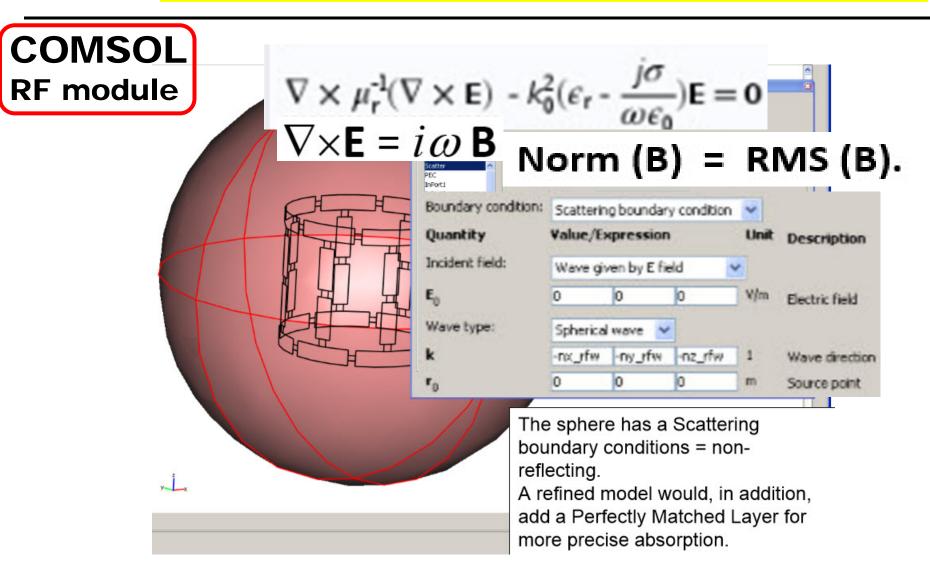


Each flap represents a simple circuit or port element such as a 50 Ohm feed or a tuning capacitor.

(Standard finite element modeling approach for RF and Microwave components)



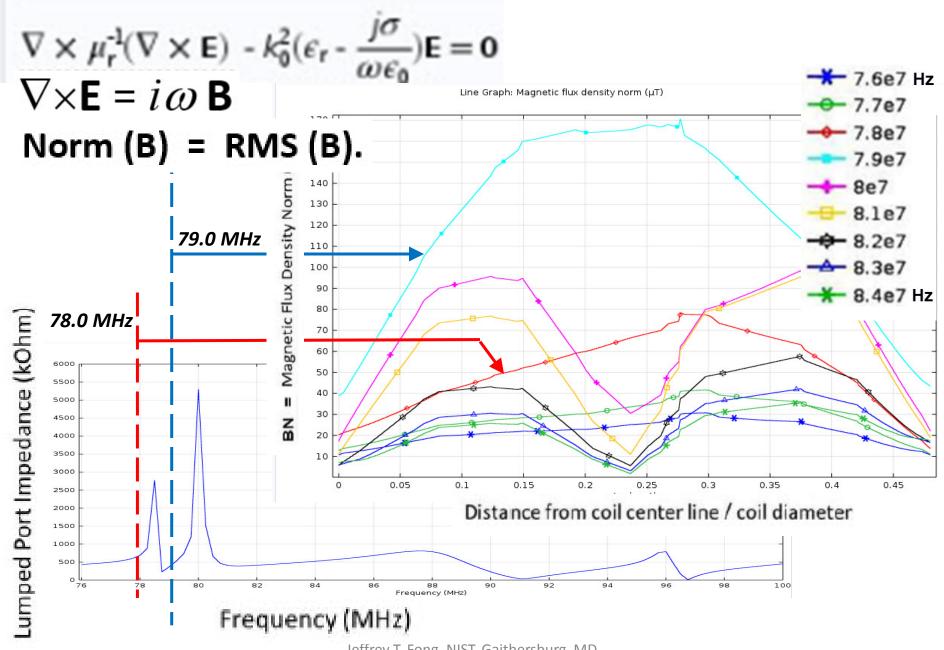




Jeffrey T. Fong, NIST, Gaithersburg, MD

20899 USA. Tel: 1-301-975-8217

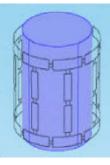
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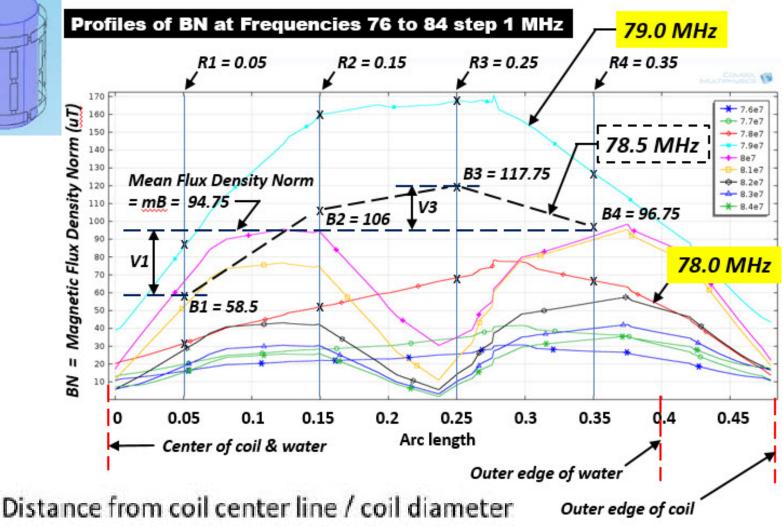


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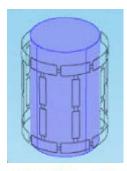




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			X4			
-1	-1	-1	+1	+1	+1	-1
+1	-1	-1	-1	-1	+1	+1
-1	+1	-1	-1	+1	-1	+1
+1	+1	-1	+1	-1	-1	-1
-1	-1	+1	+1	-1	-1	+1
+1	-1	+1	-1	+1	-1	-1
-1	+1	+1	-1	-1	+1	-1
+1	+1	+1	+1	+1	+1	+1
+1	+1	+1	-1	-1	-1	+1
-1	+1	+1	+1	+1	-1	-1
+1	-1	+1	+1	-1	+1	-1
-1	-1	+1	-1	+1	+1	+1
+1	+1	-1	-1	+1	+1	-1
-1	+1	-1	+1	-1	+1	+1
+1	-1	-1	+1	+1	-1	+1
-1	-1	-1	-1	-1	-1	-1

	X1	X2	X3	X4	X5	X6	X7
	Sigma	Epsilonr	С	V0	w1	L3	bet2
Base Run (00)	0.0001	80	177	500	80	35	5
Unit	S/m	1	рF	volt	mm	mm	degree
+/- variation	10 %	5 %	2 %	2 %	5 %	10 %	10 %
Run No. (01)	0.00009	76	173.46	510	84	38.5	4.5
Run No. (01)	0.00003	76	173.46	490	76	38.5	5.5
Run No. (02)	0.000011	84	173.46	490	84	31.5	5.5
Run No. (04)	0.00003	84	173.46	510	76	31.5	4.5
Run No. (04)	0.00011	76	180.54	510	76	31.5	5.5
Run No. (06)	0.00011	76	180.54	490	84	31.5	4.5
Run No. (07)	0.00009	84	180.54	490	76	38.5	4.5
Run No. (08)	0.00011	84	180.54	510	84	38.5	5.5
Run No. (09)	0.00011	84	180.54	490	76	31.5	5.5
Run No. (10)	0.00009	84	180.54	510	84	31.5	4.5
Run No. (11)	0.00011	76	180.54	510	76	38.5	4.5
Run No. (12)	0.00009	76	180.54	490	84	38.5	5.5
Run No. (13)	0.00011	84	173.46	490	84	38.5	4.5
Run No. (14)	0.00009	84	173.46	510	76	38.5	5.5
Run No. (15)	0.00011	76	173.46	510	84	31.5	5.5
Run No. (16)	0.00009	76	173.46	490	76	31.5	4.5

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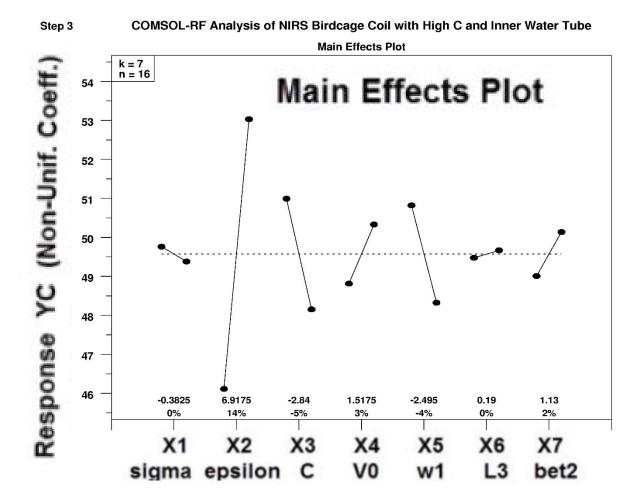


#### 760file1.txt - Notepad File Edit Format View Help Filename: 760file1.txt Date: June 25, 760file2.txt - Notepad Num of Factors 7 factors Edit Format View File Help X1 X2 X3 X4 X5 X6 X7 key to factors Filename: 760file2.txt Date: Aug. 10, 2014 symbol (on a newline factor name Elec. Conductivity of Water Num of Factors sigma Relative Permitivity of Water epsilon num of runs Capacitance 16 Voltage num of runs chosen for DOF VØ Ring Width 16 w1 runs number Strip Gap Length 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 Ring Gap Angle key to results het2 center Point values YC result name symbol (next line) 0.0001 80 177 500 variability (%) Non-Uniformity Coeff. 10.0 5.0 2.0 2.0 5.0 10.0 10.0 YC results for runs 46.89 42.92 49.28 52.17 57.99 43.01 44.73 50.58 54.25 51.86 48.95 45.52 46.34 47.85 60.62 46.50 50.63

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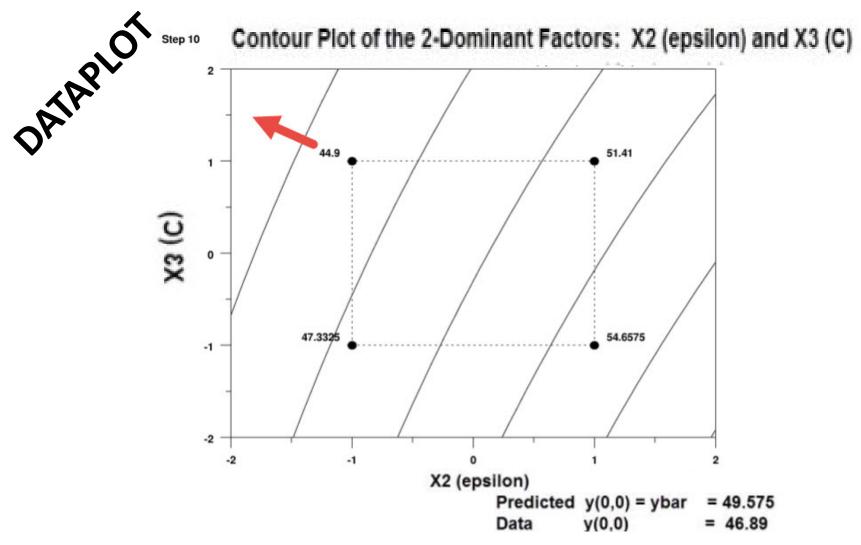
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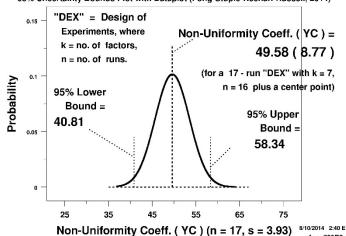
Jeffrey T. Fong, NIST, Gaithersburg, MD 20899 USA. Tel: 1-301-975-8217 Email: fong@nist.gov

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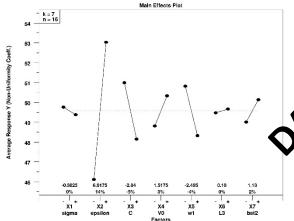


#### Non-Uniformity of NIRS Coil Magnetic Flux Density in Inner Water Tube 95% Uncertainty Bounds Plot with Dataplot (Fong-Stupic-Keenan-Russek, 2014)

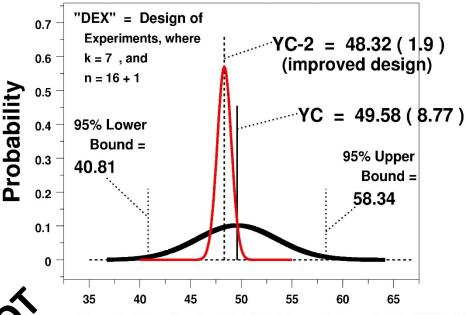


#### Step 3 COMSOL-RF Analysis of NIRS Birdcage Coil with High C and Inner Water Tube

sigma = 0.0001 +/- 10 %, epsilon = 80 +/- 5 %, C = 177 +/- 2 %, V0 = 500 +/- 2 %



#### Non-Uniformity of NIRS Coil Magnetic Flux Density in Inner Water Tube 95% Uncertainty Bounds Plot with Dataplot (Fong-Stupic-Keenan-Russek, 2014)



Non-Uniformity Coeff. ( YC ) (n = 17, s = 3.93)  $^{9/09/2014}$  11:20 EDT fong760R9a.dp sigma = 0.0001 +/- 10 %, epsilon = 80 +/- 5 %, C = 177 +/- 2 %, V0 = 500 +/- 2 %

Before:

$$NUC = 49.58(8.77)$$

After:

$$NUC = 48.32(1.90)$$



#### Future Work

- 1. A new model with geometry and physics comparable to an actual coil.
- 2. Application of the DOE approach to the new model.

Jeffrey T. Fong, NIST, Gaithersburg, MD 20899 USA. Tel: 1-301-975-8217

Email: fong@nist.gov

3. Experimental verification of the newly-optimized model.



### Disclaimer

Certain commercial equipment, instruments, materials, or computer software are identified in this talk in order to specify the experimental or computational procedure adequately. Such identification is not intended to imply recommendation or endorsement by the National Institute of Standards & Technology, nor is it intended to imply that the materials, equipment, or software identified are necessarily the best available for the purpose.



#### A Biographical Sketch of the Speaker



Dr. Jeffrey T. Fong has been Physicist and Project Manager at the Applied and Computational Mathematics Division, Information Technology Laboratory, National Institute of Standards and Technology (NIST), Gaithersburg, MD, since 1966.

He was educated at the University of Hong Kong (B.Sc., Engineering, first class honors, 1955), Columbia University (M.S., Engineering Mechanics, 1961), and Stanford (Ph.D., Applied Mechanics and Mathematics, 1966). Prior to 1966, he worked as a design engineer (1955-63) on numerous power plants (hydro, fossil-fuel, nuclear) at Ebasco Services, Inc., in New York City, and as teaching & research assistant (1963-66) on engineering mechanics at Stanford University.

During his 40+ years at NIST, he has conducted research, provided consulting services, and taught numerous short courses on mathematical and computational modeling with uncertainty estimation for fatigue, fracture, high-temperature creep, nondestructive evaluation, electromagnetic behavior, and failure analysis of a broad range of materials ranging from paper, ceramics, glass, to polymers, composites, metals, semiconductors, and biological tissues.

A licensed professional engineer (P.E.) in the State of New York since 1962 and a chartered civil engineer in the United Kingdom and British Commonwealth (A.M.I.C.E.) since 1968, he has authored or co-authored more than 100 technical papers, and edited or co-edited 17 national or international conference proceedings. He was elected Fellow of ASTM in 1982 and Fellow of ASME in 1984. In 1993, he was awarded the prestigious ASME Pressure Vessels and Piping Medal. Most recently, he was honored at the 2014 International Conference on Computational & Experimental Engineering & Sciences (ICCES) with a Lifetime Achievement Medal.

Since 2006, he has been Adjunct Professor of Mechanical Engineering and Mechanics at Drexel University and taught a graduate-level 3-credit course on "Finite Element Method Uncertainty Analysis." Since Jan. 2010, he has given every 6 months an on-line 3-hour short course at Stanford University on "Reliability and Uncertainty Estimation of FEM Models of Composite Structures." In 2012, he was appointed Adjunct Professor of Nuclear and Risk Engineering at the City University of Hong Kong, and Distinguished Guest Professor at the East China University of Science & Technology, Shanghai, China, to teach annually a 1credit 16-hour short course on "Engineering Reliability and Risk Analysis."

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